Abstracts

Analysis of Trapped Image Guides Using Effective Dielectric Constants and Surface Impedances

W.B. Zhou and T. Itoh. "Analysis of Trapped Image Guides Using Effective Dielectric Constants and Surface Impedances." 1982 MTT-S International Microwave Symposium Digest 82.1 (1982 [MWSYM]): 295-297.

Trapped image guides are analyzed using a new method. The results agree much better with experimental data than those previously derived from a simple effective dielectric constant approach.

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